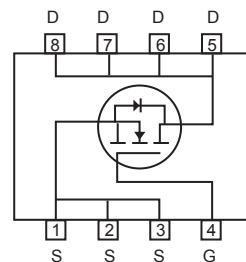
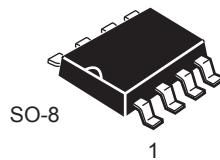


N-Channel Enhancement Mode Field Effect Transistor

FEATURES

- 30V, 14A, $R_{DS(ON)} = 7.8\text{m}\Omega$ @ $V_{GS} = 10\text{V}$.
 $R_{DS(ON)} = 11.5\text{m}\Omega$ @ $V_{GS} = 4.5\text{V}$.
- Super high dense cell design for extremely low $R_{DS(ON)}$.
- High power and current handing capability.
- Lead free product is acquired.
- Surface mount Package.



ABSOLUTE MAXIMUM RATINGS

$T_A = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Limit	Units
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current-Continuous	I_D	14	A
Drain Current-Pulsed ^a	I_{DM}	50	A
Maximum Power Dissipation	P_D	2.5	W
Operating and Store Temperature Range	T_J, T_{stg}	-55 to 150	$^\circ\text{C}$

Thermal Characteristics

Parameter	Symbol	Limit	Units
Thermal Resistance, Junction-to-Ambient ^b	$R_{\theta JA}$	50	$^\circ\text{C/W}$

This is preliminary information on a new product in development now .
Details are subject to change without notice .

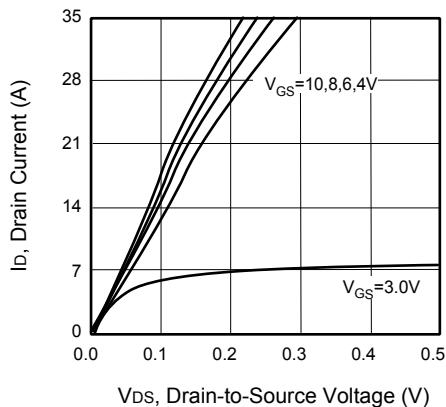
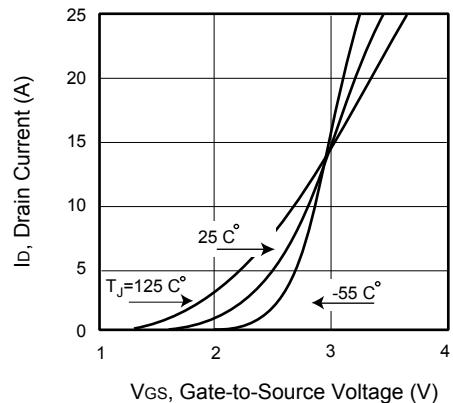
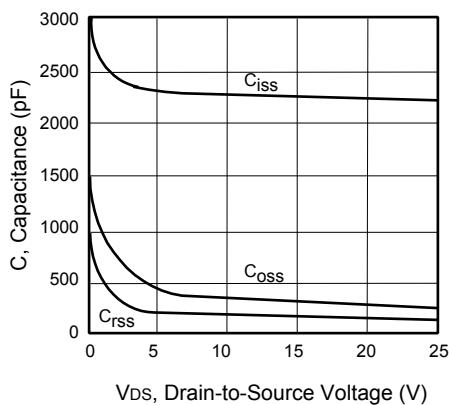
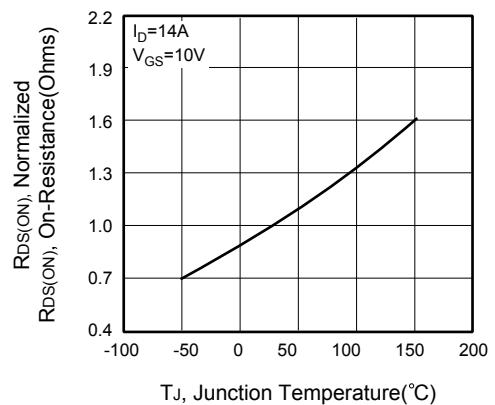
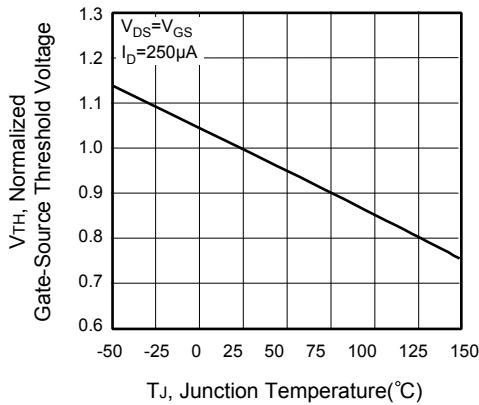
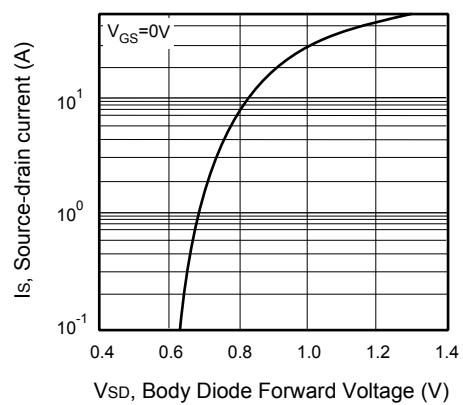
Rev 2. 2007.Oct.
<http://www.cet-mos.com>

**CEM3060****Electrical Characteristics** $T_A = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	30			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = 30\text{V}, V_{\text{GS}} = 0\text{V}$			1	μA
Gate Body Leakage Current, Forward	I_{GSSF}	$V_{\text{GS}} = 20\text{V}, V_{\text{DS}} = 0\text{V}$			100	nA
Gate Body Leakage Current, Reverse	I_{GSSR}	$V_{\text{GS}} = -20\text{V}, V_{\text{DS}} = 0\text{V}$			-100	nA
On Characteristics^c						
Gate Threshold Voltage	$V_{\text{GS(th)}}$	$V_{\text{GS}} = V_{\text{DS}}, I_D = 250\mu\text{A}$	1		3	V
Static Drain-Source	$R_{\text{DS(on)}}$	$V_{\text{GS}} = 10\text{V}, I_D = 14\text{A}$		6.5	7.8	$\text{m}\Omega$
On-Resistance		$V_{\text{GS}} = 4.5\text{V}, I_D = 14\text{A}$		8.5	11.5	$\text{m}\Omega$
Dynamic Characteristics^d						
Input Capacitance	C_{iss}	$V_{\text{DS}} = 15\text{V}, V_{\text{GS}} = 0\text{V}, f = 1.0 \text{ MHz}$		2470		pF
Output Capacitance	C_{oss}			325		pF
Reverse Transfer Capacitance	C_{rss}			185		pF
Switching Characteristics^d						
Turn-On Delay Time	$t_{\text{d(on)}}$	$V_{\text{DD}} = 15\text{V}, I_D = 1\text{A}, \square$ $V_{\text{GS}} = 10\text{V}, R_{\text{GEN}} = 6\Omega$		17	35	ns
Turn-On Rise Time	t_r			5	10	ns
Turn-Off Delay Time	$t_{\text{d(off)}}$			50	100	ns
Turn-Off Fall Time	t_f			10	20	ns
Total Gate Charge	Q_g	$V_{\text{DS}} = 15\text{V}, I_D = 14\text{A}, V_{\text{GS}} = 5\text{V}$		16	20	nC
Gate-Source Charge	Q_{gs}			5		nC
Gate-Drain Charge	Q_{gd}			3		nC
Drain-Source Diode Characteristics and Maximum Ratings						
Drain-Source Diode Forward Current ^b	I_s				14	A
Drain-Source Diode Forward Voltage ^c	V_{SD}	$V_{\text{GS}} = 0\text{V}, I_s = 2\text{A}$			1.3	V

Notes : □

- a.Repetitive Rating : Pulse width limited by maximum junction temperature.□
- b.Surface Mounted on FR4 Board, t ≤ 10 sec.□
- c.Pulse Test : Pulse Width ≤ 300μs, Duty Cycle ≤ 2%.□
- d.Guaranteed by design, not subject to production testing.□

**Figure 1. Output Characteristics****Figure 2. Transfer Characteristics****Figure 3. Capacitance****Figure 4. On-Resistance Variation with Temperature****Figure 5. Gate Threshold Variation with Temperature****Figure 6. Body Diode Forward Voltage Variation with Source Current**

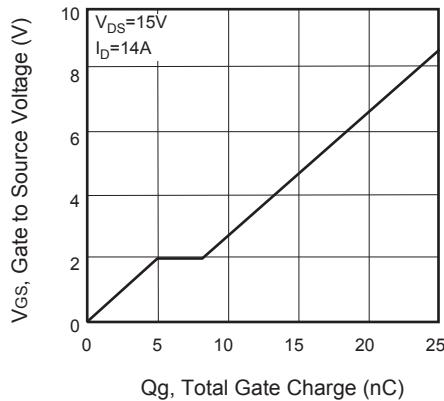


Figure 7. Gate Charge

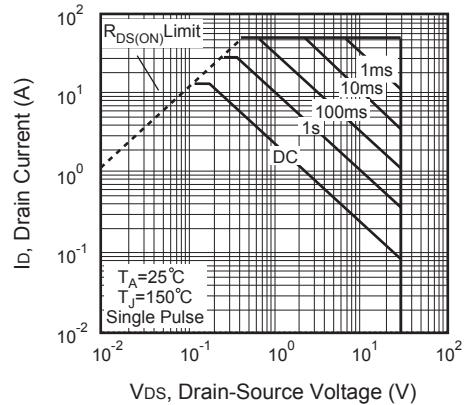


Figure 8. Maximum Safe Operating Area

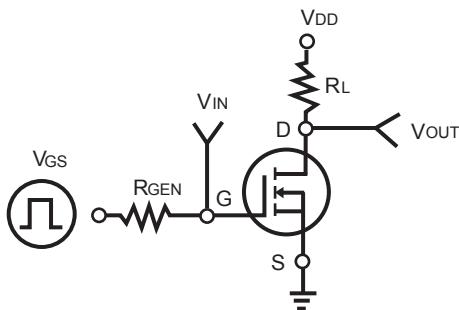


Figure 9. Switching Test Circuit

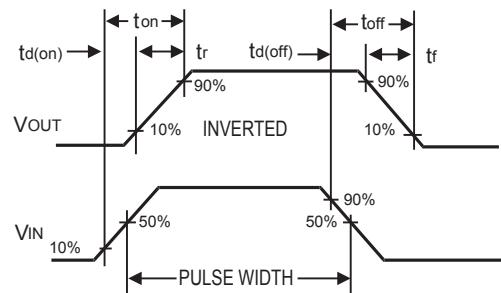


Figure 10. Switching Waveforms

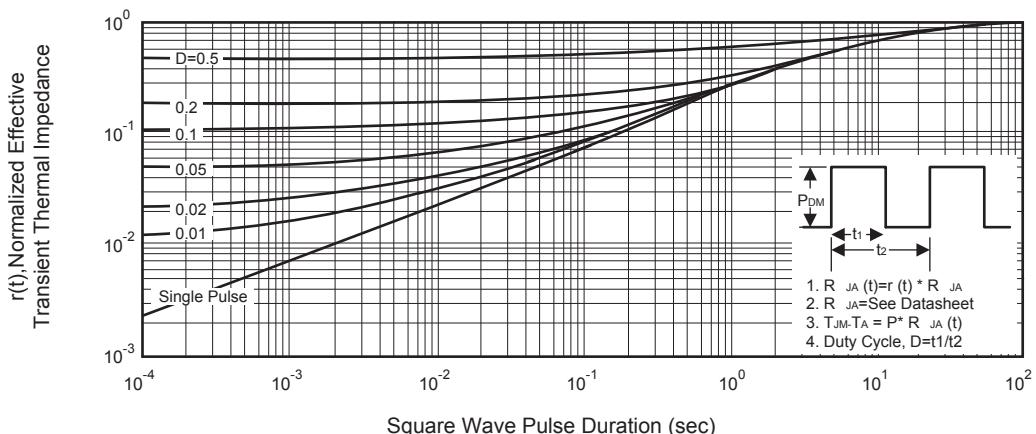


Figure 11. Normalized Thermal Transient Impedance Curve